ALPHA & OMEGA SEMICONDUCTOR

# AOTF3N80

## 800V, 2.8A N-Channel MOSFET

### General Description

The AOTF3N80 has been fabricated using an advanced high voltage MOSFET process that is designed to deliver high levels of performance and robustness in popular AC-DC applications.By providing low $R_{DS(on)}$, $C_{iss}$ and $C_{rss}$ along with guaranteed avalanche capability this part can be adopted quickly into new and existing offline power supply designs.

For Halogen Free add "L" suffix to part number: AOTF3N80L

### Product Summary

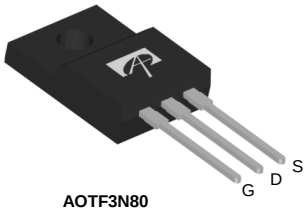
| | |
|---|---|
| $V_{DS}$ | 900V@150℃ |
| $I_D$ (at $V_{GS}$=10V) | 2.8A |
| $R_{DS(ON)}$ (at $V_{GS}$=10V) | < 4.8Ω |

100% UIS Tested
100% $R_g$ Tested

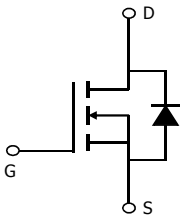
RoHS Compliant

**Top View**

**TO-220F**




**AOTF3N80**




**Absolute Maximum Ratings $T_A$=25℃ unless otherwise noted**

| Parameter | | Symbol | AOTF3N80 | Units |
|---|---|---|---|---|
| Drain-Source Voltage | | $V_{DS}$ | 800 | V |
| Gate-Source Voltage | | $V_{GS}$ | ±30 | V |
| Continuous Drain Current | $T_C$=25℃ | $I_D$ | 2.8* | A |
| | $T_C$=100℃ | | 1.8* | |
| Pulsed Drain Current [C] | | $I_{DM}$ | 9 | |
| Avalanche Current [C] | | $I_{AR}$ | 2.2 | A |
| Repetitive avalanche energy [C] | | $E_{AR}$ | 72 | mJ |
| Single pulsed avalanche energy [G] | | $E_{AS}$ | 145 | mJ |
| Peak diode recovery dv/dt | | dv/dt | 5 | V/ns |
| Power Dissipation [B] | $T_C$=25℃ | $P_D$ | 35 | W |
| | Derate above 25°C | | 0.3 | W/ °C |
| Junction and Storage Temperature Range | | $T_J$, $T_{STG}$ | -55 to 150 | ℃ |
| Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds | | $T_L$ | 300 | ℃ |

**Thermal Characteristics**

| Parameter | Symbol | AOTF3N80 | Units |
|---|---|---|---|
| Maximum Junction-to-Ambient [A,D] | $R_{\theta JA}$ | 65 | ℃/W |
| Maximum Junction-to-Case | $R_{\theta JC}$ | 3.6 | ℃/W |

* Drain current limited by maximum junction temperature.

**Electrical Characteristics ($T_J$=25℃ unless otherwise noted)**

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|---|---|---|---|---|---|---|
| **STATIC PARAMETERS** | | | | | | |
| $BV_{DSS}$ | Drain-Source Breakdown Voltage | $I_D$=250µA, $V_{GS}$=0V, $T_J$=25℃ | 800 | | | V |
| | | $I_D$=250µA, $V_{GS}$=0V, $T_J$=150℃ | | 900 | | |
| $BV_{DSS}$ /ΔTJ | Zero Gate Voltage Drain Current | ID=250µA, VGS=0V | | 0.78 | | V/ °C |
| $I_{DSS}$ | Zero Gate Voltage Drain Current | $V_{DS}$=800V, $V_{GS}$=0V | | | 1 | µA |
| | | $V_{DS}$=640V, $T_J$=125℃ | | | 10 | |
| $I_{GSS}$ | Gate-Body leakage current | $V_{DS}$=0V, $V_{GS}$=±30V | | | ±100 | nA |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{DS}$=5V, $I_D$=250µA | 3.3 | 4.2 | 4.5 | V |
| $R_{DS(ON)}$ | Static Drain-Source On-Resistance | $V_{GS}$=10V, $I_D$=1.5A | | 3.8 | 4.8 | Ω |
| $g_{FS}$ | Forward Transconductance | $V_{DS}$=40V, $I_D$=1.5A | | 2.5 | | S |
| $V_{SD}$ | Diode Forward Voltage | $I_S$=1A,$V_{GS}$=0V | | 0.77 | 1 | V |
| $I_S$ | Maximum Body-Diode Continuous Current | | | | 2.8 | A |
| $I_{SM}$ | Maximum Body-Diode Pulsed Current | | | | 9 | A |
| **DYNAMIC PARAMETERS** | | | | | | |
| $C_{iss}$ | Input Capacitance | $V_{GS}$=0V, $V_{DS}$=25V, f=1MHz | | 510 | | pF |
| $C_{oss}$ | Output Capacitance | | | 39 | | pF |
| $C_{rss}$ | Reverse Transfer Capacitance | | | 3.7 | | pF |
| $R_g$ | Gate resistance | $V_{GS}$=0V, $V_{DS}$=0V, f=1MHz | | 2.9 | | Ω |
| **SWITCHING PARAMETERS** | | | | | | |
| $Q_g$ | Total Gate Charge | $V_{GS}$=10V, $V_{DS}$=640V, $I_D$=3A | | 10 | | nC |
| $Q_{gs}$ | Gate Source Charge | | | 2.6 | | nC |
| $Q_{gd}$ | Gate Drain Charge | | | 2.9 | | nC |
| $t_{D(on)}$ | Turn-On DelayTime | $V_{GS}$=10V, $V_{DS}$=400V, $I_D$=3A, $R_G$=25Ω | | 21 | | ns |
| $t_r$ | Turn-On Rise Time | | | 25 | | ns |
| $t_{D(off)}$ | Turn-Off DelayTime | | | 34 | | ns |
| $t_f$ | Turn-Off Fall Time | | | 19 | | ns |
| $t_{rr}$ | Body Diode Reverse Recovery Time | $I_F$=3A,dI/dt=100A/µs,$V_{DS}$=100V | | 344 | | ns |
| $Q_{rr}$ | Body Diode Reverse Recovery Charge | $I_F$=3A,dI/dt=100A/µs,$V_{DS}$=100V | | 2.2 | | µC |

A. The value of $R_{\theta JA}$ is measured with the device in a still air environment with $T_A$=25° C.
B. The power dissipation $P_D$ is based on $T_{J(MAX)}$=150° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
C. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}$=150° C, Ratings are based on low frequency and duty cycles to keep initial $T_J$ =25° C.
D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.
E. The static characteristics in Figures 1 to 6 are obtained using <300 µs pulses, duty cycle 0.5% max.
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}$=150° C. The SOA curve provides a single pulse rating.
G. L=60mH, $I_{AS}$=2.2A, $V_{DD}$=150V, $R_G$=25Ω, Starting $T_J$=25° C

## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

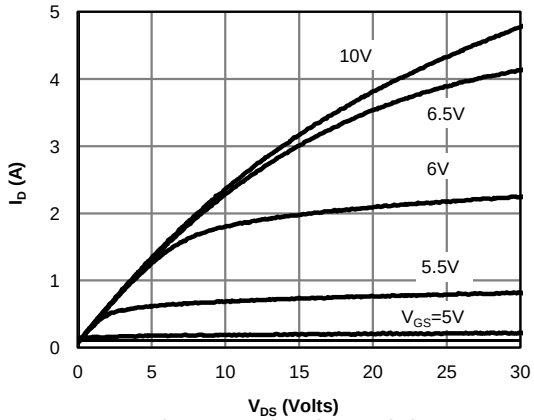


Fig 1: On-Region Characteristics

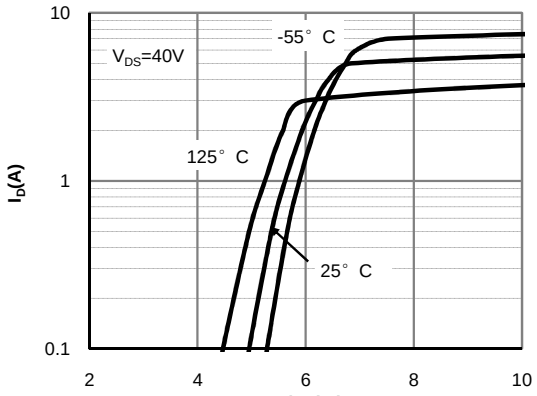


Figure 2: Transfer Characteristics

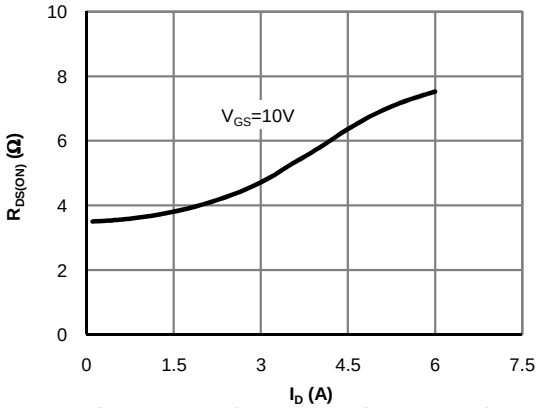


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

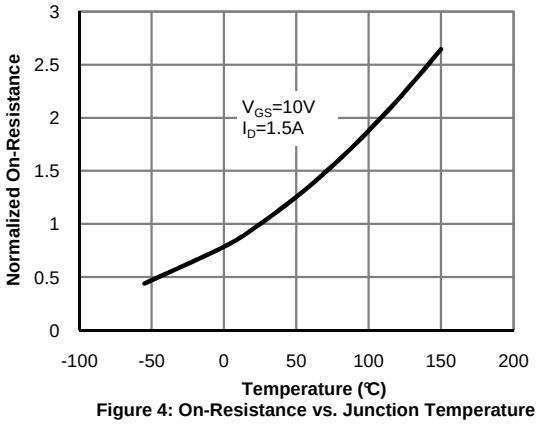


Figure 4: On-Resistance vs. Junction Temperature

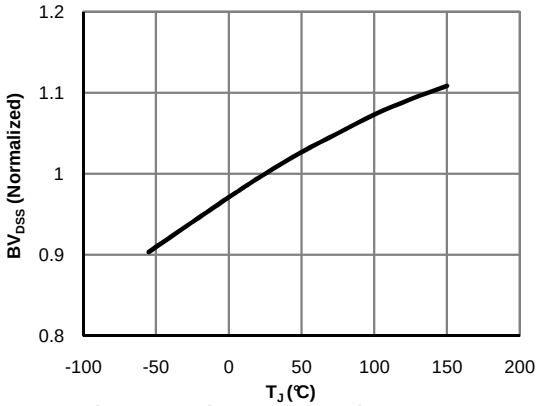


Figure 5: Break Down vs. Junction Temparature

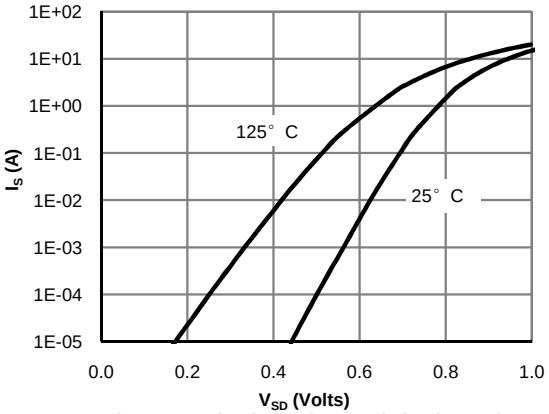


Figure 6: Body-Diode Characteristics (Note E)

## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

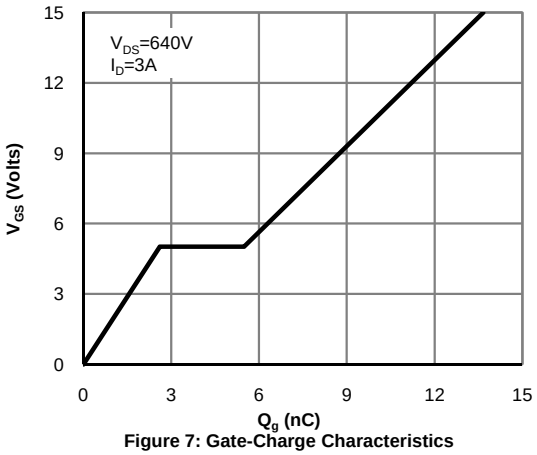



Figure 7: Gate-Charge Characteristics

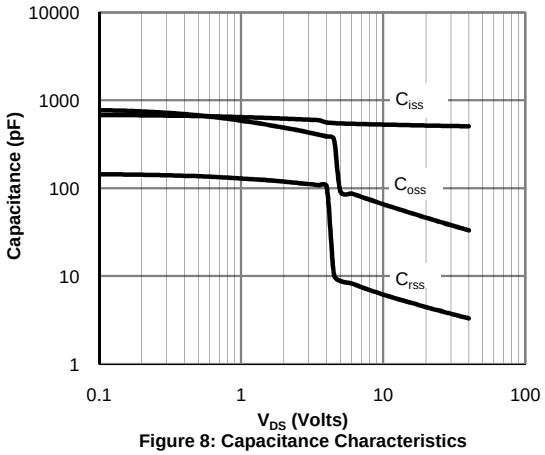



Figure 8: Capacitance Characteristics

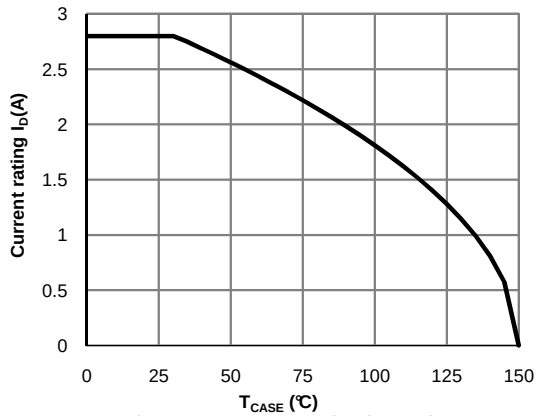



Figure 9: Current De-rating (Note B)

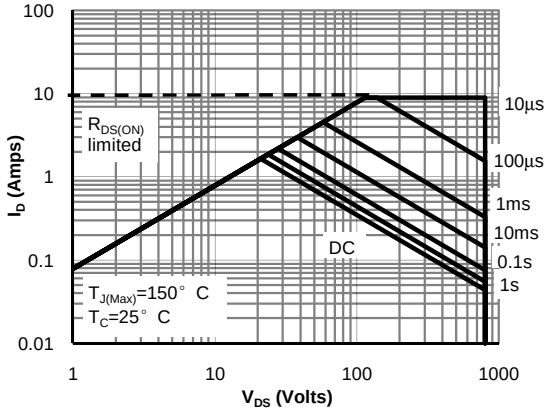



Figure 10: Maximum Forward Biased Safe Operating Area for AOTF3N80 (Note F)

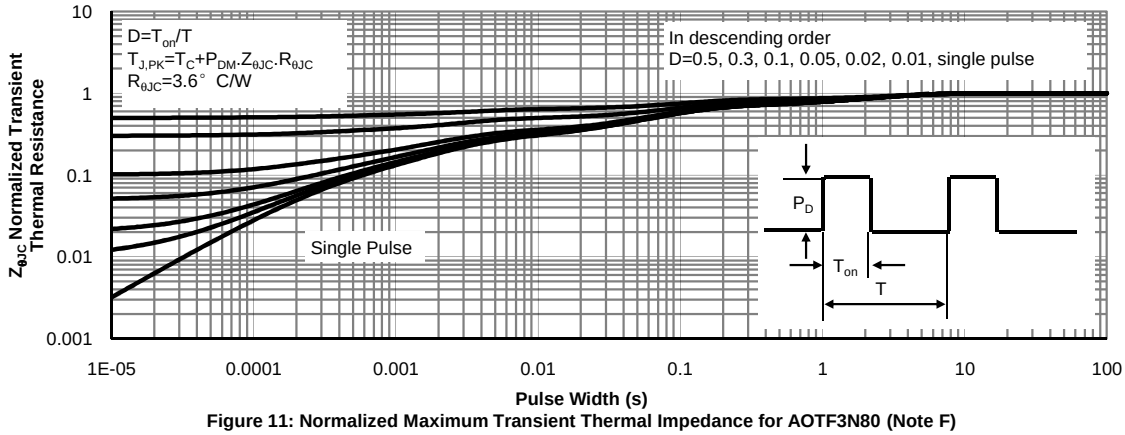
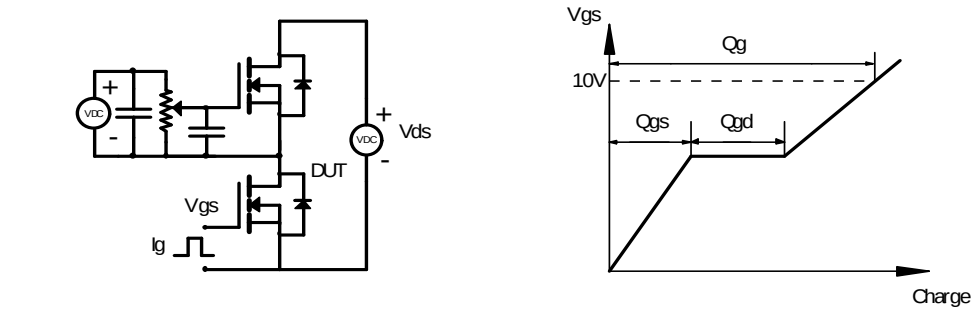
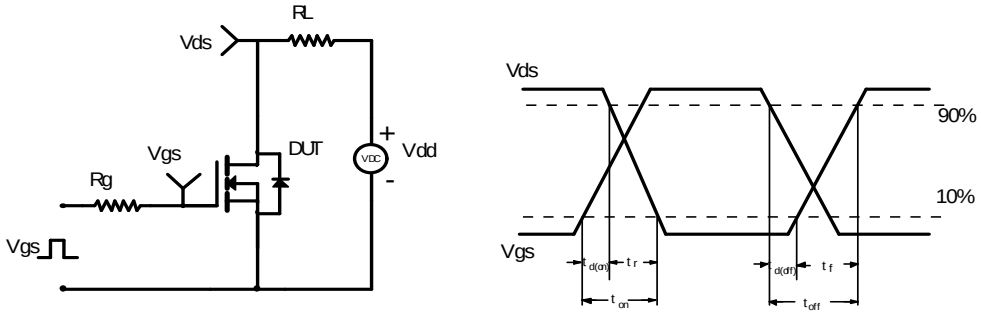



Figure 11: Normalized Maximum Transient Thermal Impedance for AOTF3N80 (Note F)

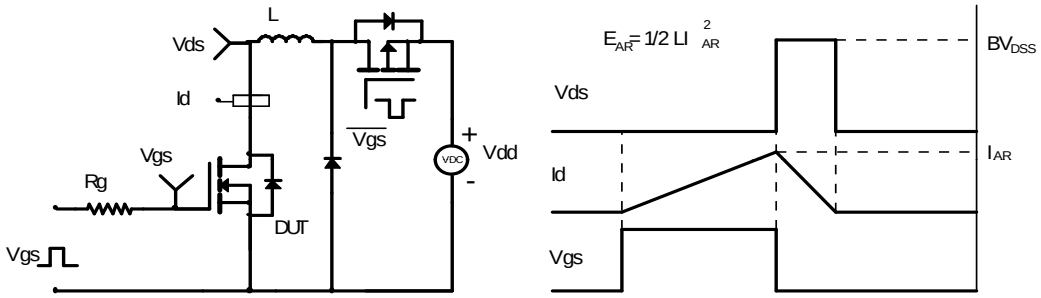
## Gate Charge Test Circuit & Waveform




## Resistive Switching Test Circuit & Waveforms




## Unclamped Inductive Switching (UIS) Test Circuit & Waveforms




## Diode Recovery Test Circuit & Waveforms